

AMENDMENTS TO THE SPECIFICATION

Please amend the specification as follows.

At paragraph [0001]:

[0001] This application is related to ~~U.S. patent application serial no. [[attorney docket no. 200208754-1 (P742US)]]~~ U.S. Patent Application Publication No. 2005-0040900, entitled "METHOD AND SYSTEM FOR CALIBRATION OF A VOLTAGE CONTROLLED OSCILLATOR (VCO);" ~~U.S. patent application serial no. [[attorney docket no. 200208755-1 (P743US)]]~~ U.S. Patent Application Publication No. 2005-0040901, entitled "SYSTEM AND METHOD FOR MEASURING CURRENT;" and, ~~U.S. patent application serial no. [[attorney docket no. 200208728-1 (P745US)]]~~ U.S. Patent Application Publication No. 2005-0043909, entitled "A METHOD FOR MEASURING INTEGRATED CIRCUIT PROCESSOR POWER DEMAND AND ASSOCIATED SYSTEM," filed concurrently herewith, the disclosures of which are hereby incorporated by reference herein in their entirety.

At paragraph [0025]:

[0025] Micro-controller 104 uses ammeters 112, which may be high-precision voltmeters, to measure CPU power. Ammeters 112 are used to calculate the current flowing into the CPU by measuring the voltage drop across a parasitic resistance, such as the resistance of the CPU package or the resistance of the power supply grid. Alternatively, micro-controller 103 may use a predetermined resistance value or may calculate the parasitic resistance, for example, through a calibration operation. The voltage and resistance values are used to calculate current and power for the CPU. A method and system for calibrating ammeters on a CPU die is disclosed in concurrently filed, copending ~~U.S. patent application serial no. [[attorney docket no. 200208728-1]]~~ U.S. Patent Application Publication No. 2005-0043909, entitled A METHOD OF AND SYSTEM FOR CONTINUOUS ON-DIE AMMETER CALIBRATION TO COMPENSATE FOR TEMPERATURE AND DRIFT ON-BOARD A MICROPROCESSOR, the disclosure of which is hereby incorporated by reference herein.